

Notice of References Cited	Application/Control No. 10/026,232	Applicant(s)/Patent Under Reexamination HASNAIN ET AL.	
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	X	Yeo et al. ("Effect of the (1010)..."), July 1998, IEEE Journal of Quantum Electronics, Vol. 34, No. 7, pages 1270-1279.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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